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MAY 2015

FQB1P50

P-Channel QFET® MOSFET

- 500 V, - 1.5 A, 10.5 Ω

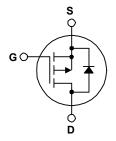
Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- 1.5 A, 500 V, $R_{DS(on)}$ = 10.5 Ω (Max.) @ V_{GS} = 10 V, I_{D} = 0.75 A
- Low Gate Charge (Typ. 11 nC)
- Low Crss (Typ. 6.0 pF)
- 100% Avalanche Tested
- RoHS Compliant





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQB1P50TM	Unit
V _{DSS}	Drain-Source Voltage		-500	V
I _D	Drain Current - Continuous (T _C = 25°C)		-1.5	Α
	- Continuous (T _C = 100°C)		-0.95	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	-6.0	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	110	mJ
I _{AR}	Avalanche Current	(Note 1)	-1.5	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	6.3	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns
P _D	Power Dissipation (T _A = 25°C) *		3.13	W
_	Power Dissipation (T _C = 25°C)		63	W
	- Derate above 25°C		0.51	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQB1P50TM	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	1.98	
Б	Thermal Resistance, Junction to Ambient (minimum pad of 2 oz copper), Max.	62.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (1 in ² pad of 2 oz copper), Max.	40	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQB1P50	FQB1P50TM	D2-PAK	330mm	24mm	800

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Tc	=	25°	С	unless	otherwi	se	noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-500			V
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -500 V, V _{GS} = 0 V V _{DS} = -400 V, T _C = 125°C			-1 -10	μ Α μ Α
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.0		-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, I_D = -0.75 \text{ A}$		8.0	10.5	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = -50 \text{ V}, I_{D} = -0.75 \text{ A}$		1.26		S

Dynamic Characteristics

C _{iss}	Input Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$	 270	350	pF
C _{oss}	Output Capacitance	f = 1.0 MHz	 40	50	pF
C_{rss}	Reverse Transfer Capacitance		 6.0	8.0	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	V _{DD} = -250 V, I _D = -1.5 A,	 9.0	30	ns
t _r	Turn-On Rise Time	$R_{G} = 25 \Omega$	 25	60	ns
$t_{d(off)}$	Turn-Off Delay Time	1 1G - 20 32	 27	65	ns
t _f	Turn-Off Fall Time	(Note 4)	 30	70	ns
Q_g	Total Gate Charge	$V_{DS} = -400 \text{ V}, I_{D} = -1.5 \text{ A},$	 11	14	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -10 V	 2.0		nC
Q_{gd}	Gate-Drain Charge	(Note 4)	 5.6		nC

Drain-Source Diode Characteristics and Maximum Ratings

Diam	-ocurce blode characteristics a	ila maxiillaili Ratiligo				
IS	Maximum Continuous Drain-Source Diode Forward Current				-1.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	Maximum Pulsed Drain-Source Diode Forward Current			-6.0	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -1.5 \text{ A}$			-5.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = -1.5 \text{ A,}$		200		ns
Q_{rr}	Reverse Recovery Charge	$dI_{F} / dt = 100 A/\mu s$		0.7		μC

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 88mH, I_{AS} = -1.5A, V_{DD} = -50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} ≤ -1.5A, di/dt ≤ 200A/ μ s, V_{DD} ≤ BV $_{DSS}$, Starting T_J = 25°C

- Essentially independent of operating temperature

Typical Characteristics

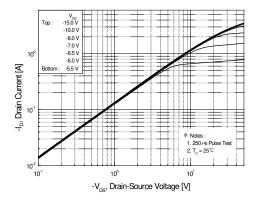


Figure 1. On-Region Characteristics

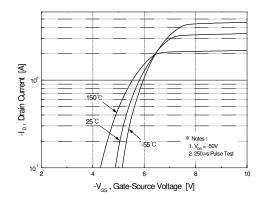


Figure 2. Transfer Characteristics

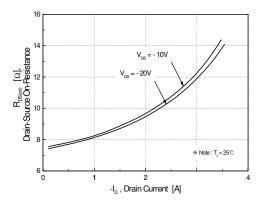


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

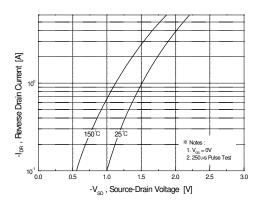


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

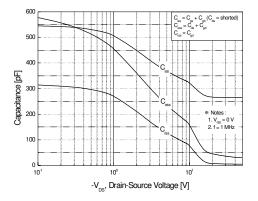


Figure 5. Capacitance Characteristics

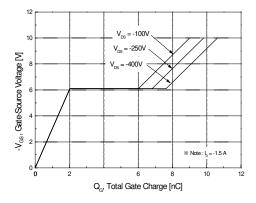


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

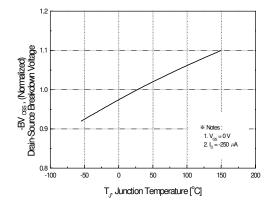
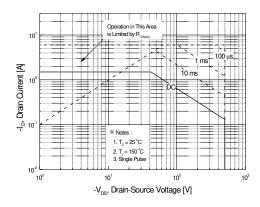


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



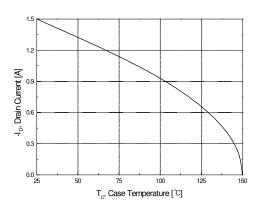


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

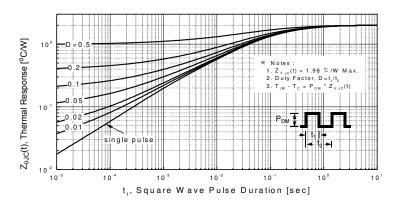


Figure 11. Transient Thermal Response Curve



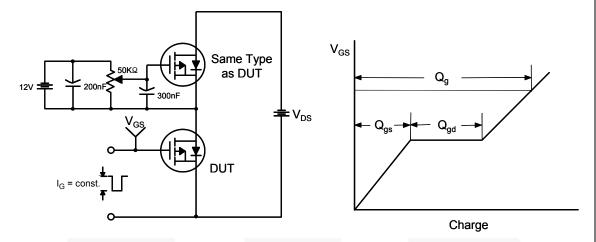


Figure 13. Resistive Switching Test Circuit & Waveforms

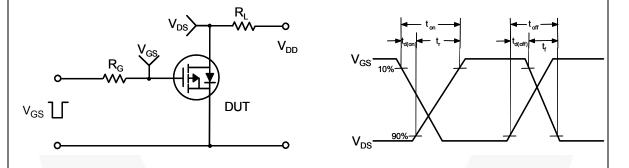


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

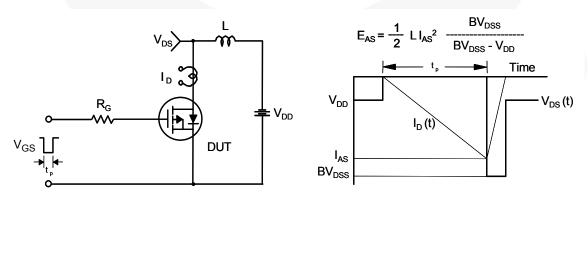
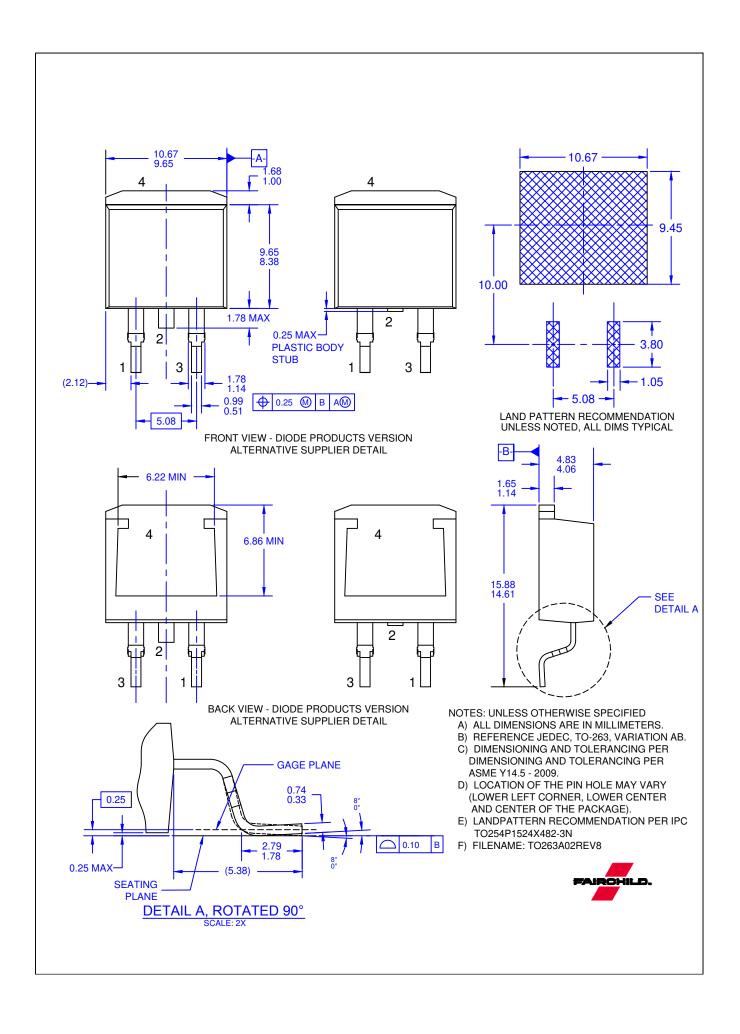


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms DUT I_{SD} Driver Compliment of DUT
 Image: Section of the property (N-Channel) $\prod V_{GS}$ • dv/dt controlled by R_G • I_{SD} controlled by pulse period Gate Pulse Width V_{GS} Gate Pulse Period 10V (Driver) **Body Diode Reverse Current** I_{SD} (DUT) di/dt I_{FM} , Body Diode Forward Current V_{DS} V_{SD} (DUT) Body Diode Forward Voltage Drop Body Diode Recovery dv/dt



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